Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/070,515	LLOYD ET AL.	
Examiner	Art Unit	
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	SEARCHED					
Class	Subclass	Date	Examiner			
370	235	0.2/03/07	CH.			
370	254					
709	2214					
370	401					
370	3521					
370	353					
370	2311					
370	235	:				

INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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